

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/582,788 ONO ET AL.	
		Examiner	Art Unit John L. Goff	1791 Page 1 of 1

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	U	Machine translation of JP 2001348786 date unknown
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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